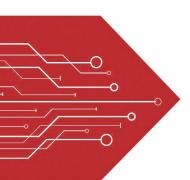
# MSKSEMI















**ESD** 

TVS

TSS

MOV

**GDT** 

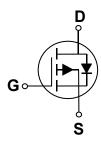
**PLED** 

# Brodnet data speet

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SOT-23



#### **Features**

- -20V,-4.0A, RDS(ON)=50mΩ@VGS=-4.5V
- Improved dv/dt capability
- Fast switching
- Green Device Available

#### **Applications**

- Notebook
- Load Switch
- Hend-Held Instruments

BVDSS	RDSON	ID
-20V	50m $Ω$	-4.0A

## **Absolute Maximum Ratings** Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-20	V
V <sub>G</sub> S	Gate-Source Voltage	±12	V
	Drain Current – Continuous (T <sub>C</sub> =25°C)	-4.0	А
ID	Drain Current – Continuous (T <sub>C</sub> =100°C)	-2.7	Α
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	-16	А
D	Power Dissipation (Tc=25°C)	1.56	W
P <sub>D</sub>	Power Dissipation – Derate above 25°C	0.012	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		80	°C/W

#### **Electrical Characteristics** (T<sub>J</sub>=25 °C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-20			<b>V</b>
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.02		V/°C
	Dunin Course Lookens Courset	V <sub>DS</sub> =-20V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			-1	uA
I <sub>DSS</sub> Drain-Source Leakage Current	Drain-Source Leakage Current	V <sub>DS</sub> =-16V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			-10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS} = \pm 12V$ , $V_{DS} = 0V$			±100	nA

#### **On Characteristics**

R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-3A		50	65	mΩ
TOS(ON)		V <sub>GS</sub> =-2.5V , I <sub>D</sub> =-2A		65	100	11122
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA		-0.65	-1.2	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient			2		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>S</sub> =-3A		7		S

#### **Dynamic and switching Characteristics**

-						
$Q_g$	Total Gate Charge <sup>2, 3</sup>			9.6		
Qgs	Gate-Source Charge <sup>2,3</sup>	$V_{DS}$ =-10V , $V_{GS}$ =-4.5V , $I_{D}$ =-3A		1.6		nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>			2		
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2, 3</sup>		-	6	-	
Tr	Rise Time <sup>2, 3</sup>	$V_{DD}$ =-10V , $V_{GS}$ =-4.5V , $R_{G}$ =25 $\Omega$		21.6		nS
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> =-1A		51		113
T <sub>f</sub>	Fall Time <sup>2, 3</sup>			13.8		
C <sub>iss</sub>	Input Capacitance			850		
Coss	Output Capacitance	V <sub>DS</sub> =-10V , V <sub>GS</sub> =0V , F=1MHz		70		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			55		

Drain-Source Diode Characteristics and Maximum Ratings						
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	\\ -\\ -0\\   Faraa Currant			-4.0	Α
I <sub>SM</sub>	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-8.0	Α
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1.2	V

#### Note

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leq 300 us$  , duty cycle  $\leq 2\%.$
- B. Essentially independent of operating temperature.



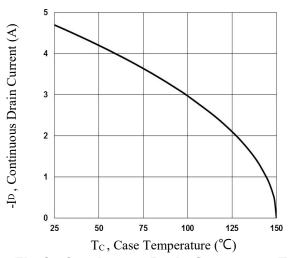


Fig.1 Continuous Drain Current vs. Tc

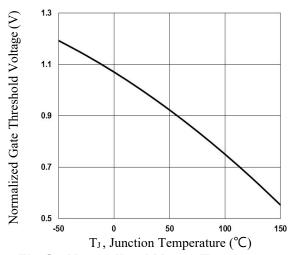


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

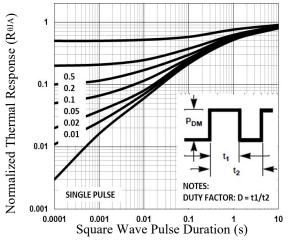


Fig.5 Normalized Transient Impedance

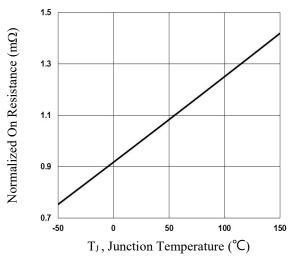


Fig.2 Normalized RDSON vs. T<sub>J</sub>

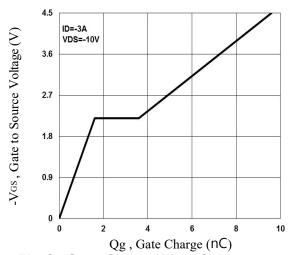


Fig.4 Gate Charge Waveform

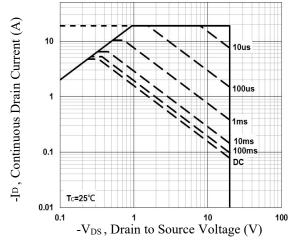
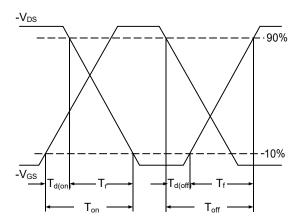


Fig.6 Maximum Safe Operation Area







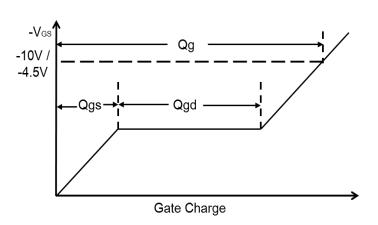
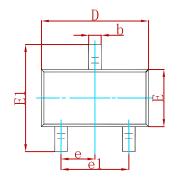
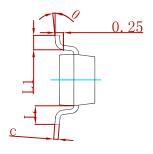
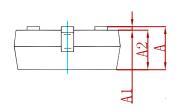


Fig.8 Gate Charge Waveform

#### **PACKAGE MECHANICAL DATA**

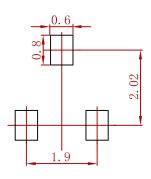






Symbol	Dimensions	Dimensions In Millimeters		s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
Е	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950	) TYP	0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022	REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

## **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

### **REEL SPECIFICATION**

P/N	PKG	QTY
IRLML6402	SOT-23	3000





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